

SEMICONDUCTOR®

November 2013

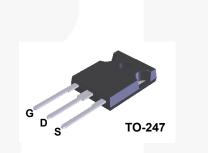
FQH44N10 N-Channel QFET[®] MOSFET 100 V, 48 A, 39 mΩ

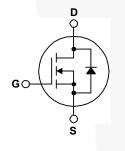
Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

Features

- 48 A, 100 V, $R_{DS(on)}$ = 39 m Ω (Max.) @ V_{GS} = 10 V, I_{D} = 24 A
- Low Gate Charge (Typ. 48 nC)
- Low Crss (Typ. 85 pF)
- 100% Avalanche Tested
- 175°C Maximum Junction Temperature Rating





Absolute Maximum Ratings T_c = 25°C unless otherwise noted.

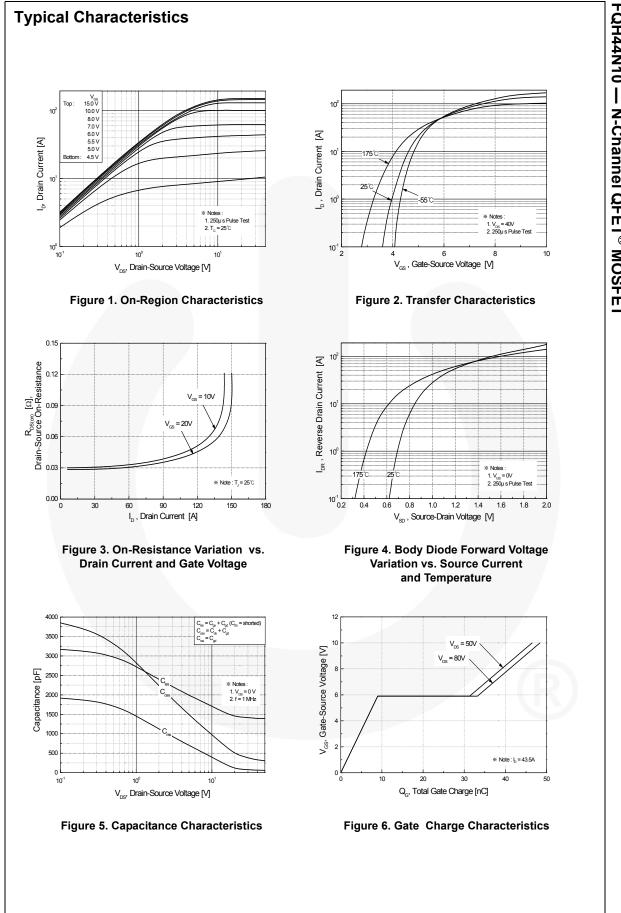
Symbol		Parameter	FQH44N10_F133	Unit		
V _{DSS}	Drain-Source Voltage			100	V	
I _D	Drain Current - Continuous (T _C = 25°C)			48	A	
		- Continuous (T _C = 100°0	34	A		
I _{DM}	Drain Current	- Pulsed	(Note 1)	192	A	
V _{GSS}	Gate-Source Voltage			± 25	V	
E _{AS}	Single Pulsed Avalanche Energy		(Note 2)	530	mJ	
I _{AR}	Avalanche Current		(Note 1)	48	Α	
E _{AR}	Repetitive Avalanche Energy		(Note 1)	18	mJ	
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	6.0	V/ns	
PD	Power Dissipation (T _C = 25°C)			180	W	
	- Derate above 25°C			1.2	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range			-55 to +175	°C	
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds			300	°C	

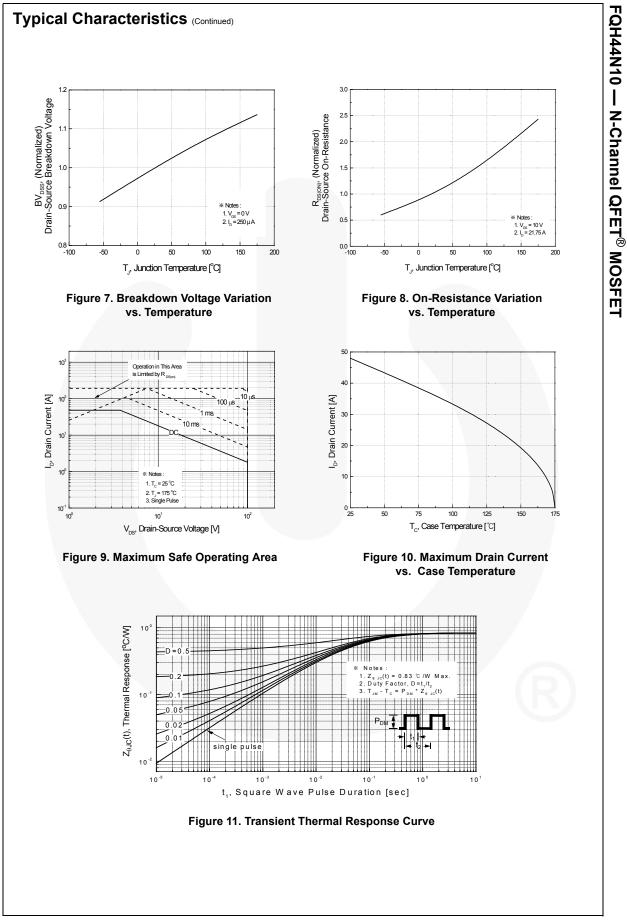
Thermal Characteristics

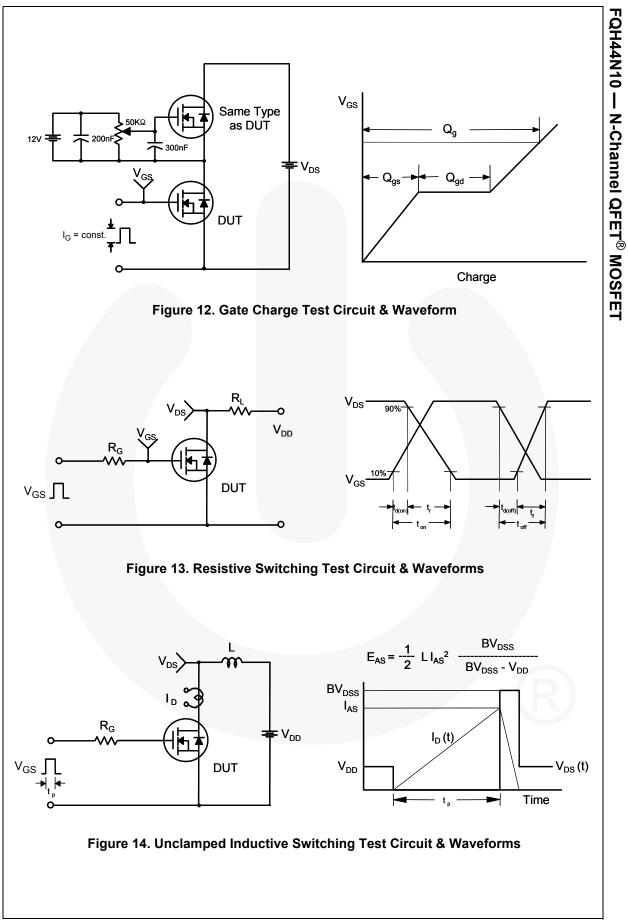
Symbol	Parameter	FQH44N10_F133	Unit	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	0.83	°C/W	
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink, Typ.	0.24	°C/W	
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction-to-Ambient, Max.	40	°C/W	

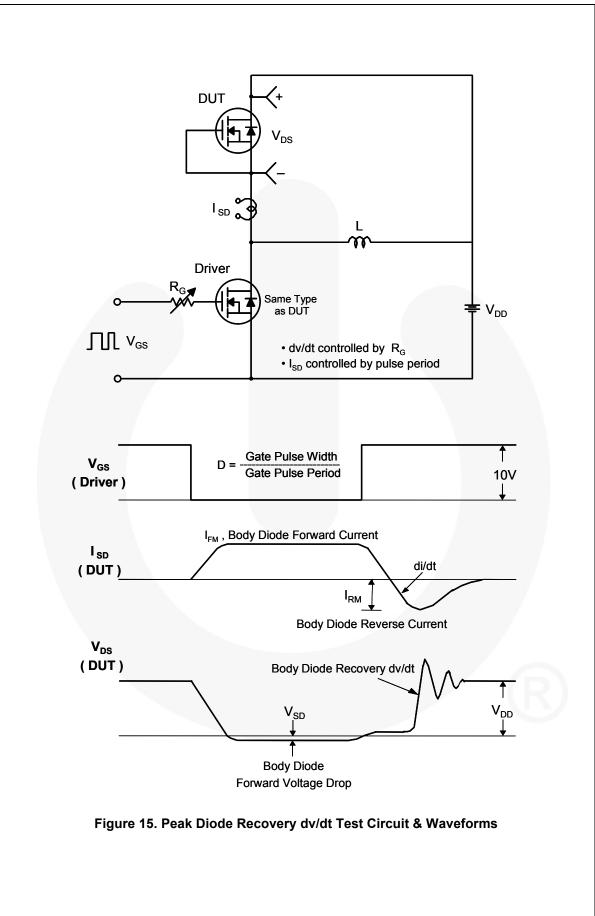
cal Cha	FQH44N10		aye	Package Packing Method Reel		126	Tape W		Quantity
cal Cha	ractoristice	FQH44N10_F133 FQH44N10 TO				A	N/A		30 units
		T _c = 25°C unl	ess otherv	vise noted.					
	Parameter			Test Conditions		Min	Тур	Мах	Unit
Drain-Sol	lics								
Drain-Source Breakdown Voltage			V_{GS} = 0 V, I_D = 250 μ A			100			V
Breakdown Voltage Temperature Coefficient		$I_D = 250 \ \mu$ A, Referenced to 25° C				0.1		V/°C	
Zero Gate	Zero Gate Voltage Drain Current		$V_{DS} = 100 V, V_{GS} = 0 V$ $V_{DS} = 80 V, T_{C} = 150^{\circ}C$					1 10	μA μA
Gate-Bod	Gate-Body Leakage Current, Forward								nA
Gate-Body Leakage Current, Reverse									nA
	<u>, , , , , , , , , , , , , , , , , , , </u>		00	- ,					
			V _{DS} =	V _{GS} , I _D = 250 μA		2.0		4.0	V
Static Dra	in-Source						0.03	0.039	Ω
Forward ⁻	Transconductance		V _{DS} = 40 V, I _D = 24 A				31		S
c Chara	cteristics								
Input Cap	acitance		V _{De} =	$25 V. V_{CC} = 0 V.$			1400	1800	pF
Output Ca	Capacitance		f = 1.0 MHz				425	550	pF
Reverse ⁻	ransfer Capacitanc	е					85	110	pF
ng Char	acteristics								
Turn-On I	Delay Time		Vpp =	50 V = 435 A			19	45	ns
Turn-On I	Rise Time		00				190	390	ns
Turn-Off I	Delay Time		0				90	190	ns
T	Fall Time				(Note 4)		100	210	ns
Turn-Off I			V _{DS} =	80 V, I _D = 43.5 A,			48	62	nC
Turn-Off I	e Charge								
Total Gate	e Charge rce Charge		V _{GS} =	2			9.0		nC
Total Gate	rce Charge		V _{GS} =	2	(Note 4)		9.0 24		nC nC
Total Gate Gate-Sou Gate-Dra	rce Charge in Charge	istics a		2	(Note 4)				-
Total Gate Gate-Sou Gate-Dra	rce Charge in Charge		nd Ma	10 V ximum Ratings	(Note 4)				-
Total Gate Gate-Sou Gate-Dra ource D Maximum	rce Charge in Charge iode Character	Source Dic	nd Ma	10 V ximum Ratings vard Current	(Note 4)		24		nC
Total Gate Gate-Sou Gate-Dra ource D Maximum Maximum	rce Charge in Charge iode Character Continuous Drain-S	Source Dic ce Diode F	nd Ma ode Forv	10 V ximum Ratings vard Current	(Note 4)				nC A
Total Gate Gate-Sou Gate-Dra ource D Maximum Maximum Drain-Sou	rce Charge in Charge iode Character Continuous Drain-S Pulsed Drain-Source	Source Dic ce Diode F	nd Ma ode Forv Forward	10 V ximum Ratings vard Current Current	(Note 4)		24 	 48 192	A A
	Gate-Body racterist Gate Three Static Dra On-Resist Forward T c Charace Input Cap Output Ca Reverse T ng Chara Turn-On E Turn-On F	Gate-Body Leakage Current, racteristics Gate Threshold Voltage Static Drain-Source On-Resistance Forward Transconductance c Characteristics Input Capacitance Output Capacitance	racteristics Gate Threshold Voltage Static Drain-Source On-Resistance Forward Transconductance c Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance ng Characteristics Turn-On Delay Time Turn-On Rise Time	Gate-Body Leakage Current, Forward V _{GS} = Gate-Body Leakage Current, Reverse V _{GS} = racteristics V _{GS} = Gate Threshold Voltage V _{DS} = Static Drain-Source V _{GS} = On-Resistance V _{DS} = Forward Transconductance V _{DS} = c Characteristics Input Capacitance Output Capacitance f = 1.0 Reverse Transfer Capacitance f = 1.0 ng Characteristics V _{DD} = Turn-On Delay Time V _{DD} = Turn-On Rise Time R _G = 2	Gate-Body Leakage Current, Forward $V_{GS} = 25 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$ racteristics $V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$ Gate Threshold Voltage $V_{DS} = V_{GS}, I_D = 250 \mu \text{A}$ Static Drain-Source On-Resistance $V_{GS} = 10 \text{ V}, I_D = 24 \text{ A}$ Forward Transconductance $V_{DS} = 40 \text{ V}, I_D = 24 \text{ A}$ c Characteristics $V_{DS} = 40 \text{ V}, I_D = 24 \text{ A}$ Input Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ Output Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHzTurn-On Delay TimeTurn-On Delay Time $V_{DD} = 50 \text{ V}, I_D = 43.5 \text{ A},$ Turn-On Rise Time $V_{GS} = 25 \Omega$	Gate-Body Leakage Current, Forward $V_{GS} = 25 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$ racteristics $V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$ Gate Threshold Voltage $V_{DS} = V_{GS}, I_D = 250 \mu \text{A}$ Static Drain-Source On-Resistance $V_{GS} = 10 \text{ V}, I_D = 24 \text{ A}$ Forward Transconductance $V_{DS} = 40 \text{ V}, I_D = 24 \text{ A}$ c Characteristics $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ Input Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ Output Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ Reverse Transfer Capacitance $V_{DD} = 50 \text{ V}, I_D = 43.5 \text{ A},$ Turn-On Delay Time $V_{DD} = 50 \text{ Q},$	Gate-Body Leakage Current, Forward $V_{GS} = 25 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$ racteristics $V_{DS} = V_{GS}, I_D = 250 \mu \text{A}$ 2.0Gate Threshold Voltage $V_{DS} = V_{GS}, I_D = 250 \mu \text{A}$ 2.0Static Drain-Source On-Resistance $V_{GS} = 10 \text{ V}, I_D = 24 \text{ A}$ Forward Transconductance $V_{DS} = 40 \text{ V}, I_D = 24 \text{ A}$ CharacteristicsInput Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ Output Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ reverse Transfer Capacitance $V_{DD} = 50 \text{ V}, I_D = 43.5 \text{ A},$ Turn-On Delay Time $V_{DD} = 50 \text{ V}, I_D = 43.5 \text{ A},$ Turn-On Rise Time $V_{DD} = 50 \text{ Q}, I_D = 43.5 \text{ A},$	Gate-Body Leakage Current, Forward $V_{GS} = 25 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$ racteristicsGate Threshold Voltage $V_{DS} = V_{GS}, I_D = 250 \mu \text{A}$ 2.0Static Drain-Source On-Resistance $V_{GS} = 10 \text{ V}, I_D = 24 \text{ A}$ 0.03Forward Transconductance $V_{DS} = 40 \text{ V}, I_D = 24 \text{ A}$ 31c CharacteristicsInput Capacitance Output Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$ 1400Output Capacitance $Y_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$ 85mg CharacteristicsTurn-On Delay Time Turn-On Rise Time $V_{DD} = 50 \text{ V}, I_D = 43.5 \text{ A}, R_G = 25 \Omega$ 19190190	Gate-Body Leakage Current, Forward $V_{GS} = 25 \text{ V}, V_{DS} = 0 \text{ V}$ 100 Gate-Body Leakage Current, Reverse $V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$ -100 racteristics Gate Threshold Voltage $V_{DS} = V_{GS}, I_D = 250 \mu \text{A}$ 2.0 4.0 Static Drain-Source On-Resistance $V_{GS} = 10 \text{ V}, I_D = 24 \text{ A}$ 0.03 0.039 Forward Transconductance $V_{DS} = 40 \text{ V}, I_D = 24 \text{ A}$ 31 c Characteristics Input Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ 1400 1800 Output Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ 425 550 Reverse Transfer Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ 425 550 Input Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ 425 550 Reverse Transfer Capacitance 85 110 Input On Delay Time Turn-On Rise Time $V_{DD} = 50 \text{ V}, I_D = 43.5 \text{ A},$ 19 45 Turn-On Rise Time $V_{DD} = 50 \text{ V}, I$

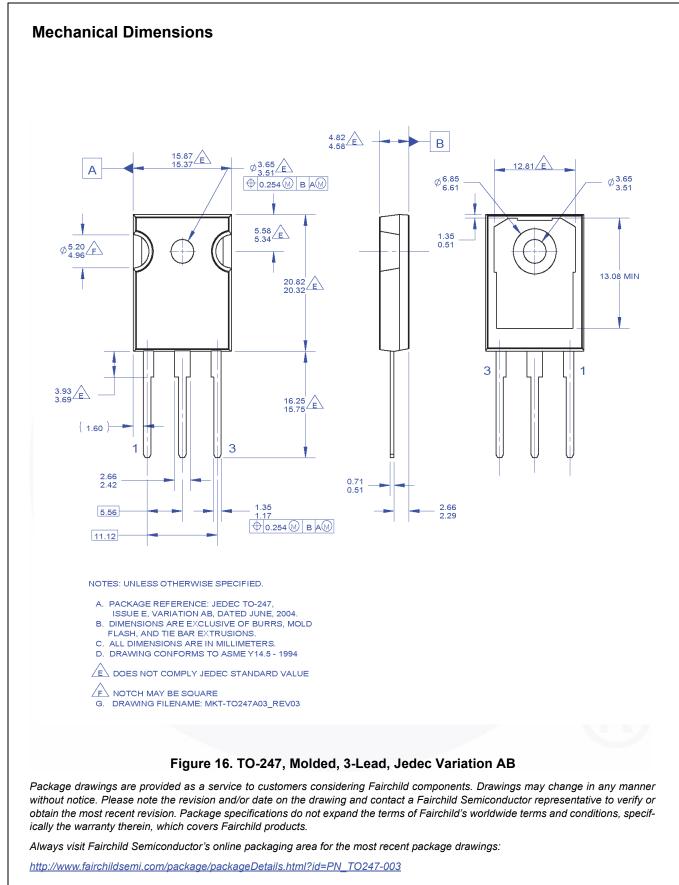
FQH44N10 — N-Channel QFET[®] MOSFET













notice to improve design.

First Production

Full Production

Preliminary

No Identification Needed

Rev. 166

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